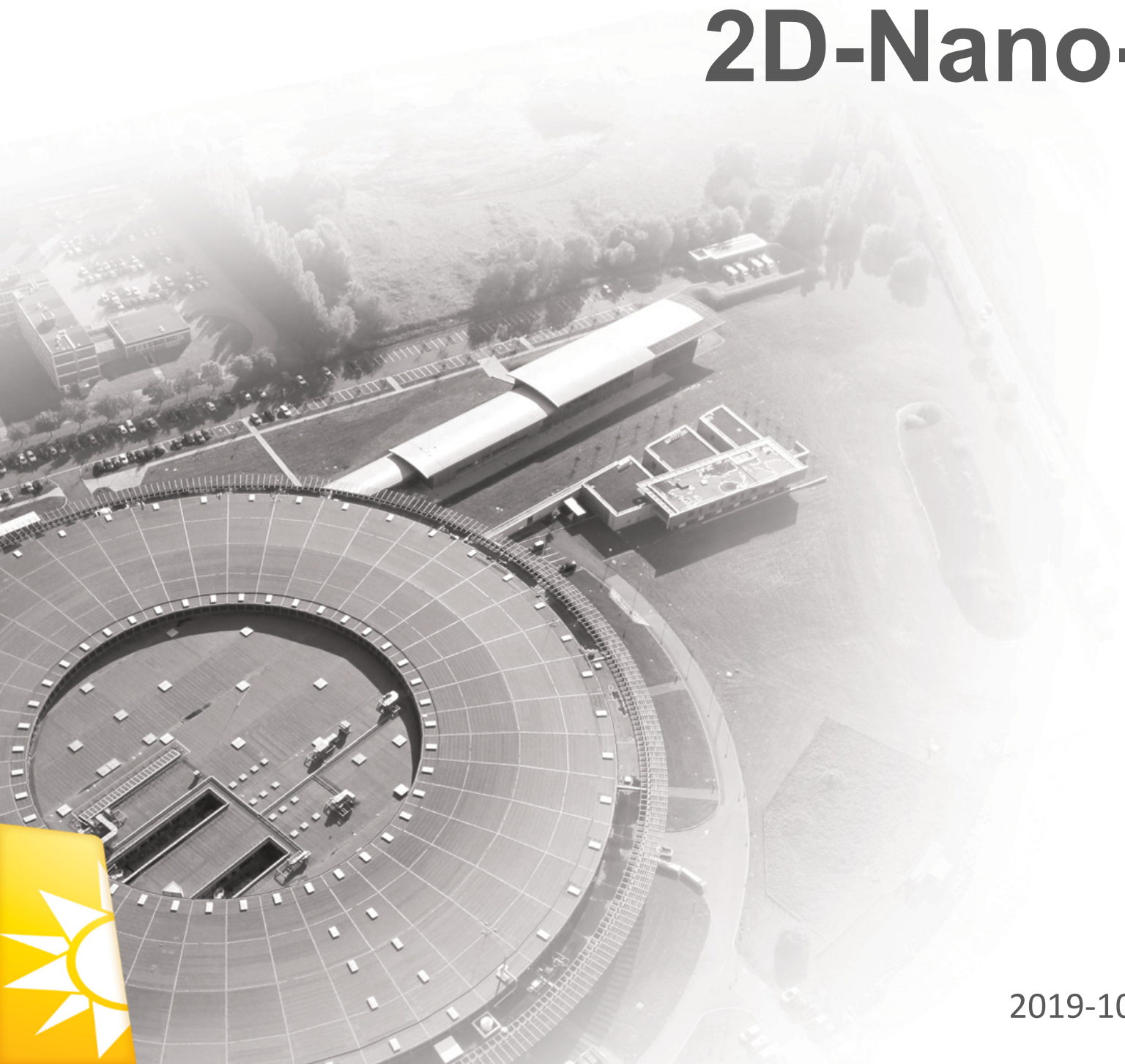


2D-Nano-Ptychography Results at the SWING Beamline



Christer Engblom, *Synchrotron Soleil*

ECA (Electronique de Contrôle et Acquisition) Group

- Electronics & Motion Control
(Specialized in motorized precision control systems)

On behalf of the Nanoprobe SWING team:

J. Perez (SWING beamline), A. Lestrade (Metrology), F. Alves (Mechanics), F. Langlois (Software & Ctrl), YM. Abiven (Electronics), F. Berenguer (CRISTAL Beamline), P. Montaville (PX1 beamline)

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 - Context & overview
 - Challenges & approach
- Nanoprobe SWING Setup
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 - Sample & OSA Stage
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Nanoprobe Project (2013-2017)

Collaboration (Synchrotron SOLEIL & MAX IV) to produce Nanoprobe endstation prototype capable of 2D- & 3D tomography on the nanometric scale.

Nanoprobe-SOLEIL (2017-)

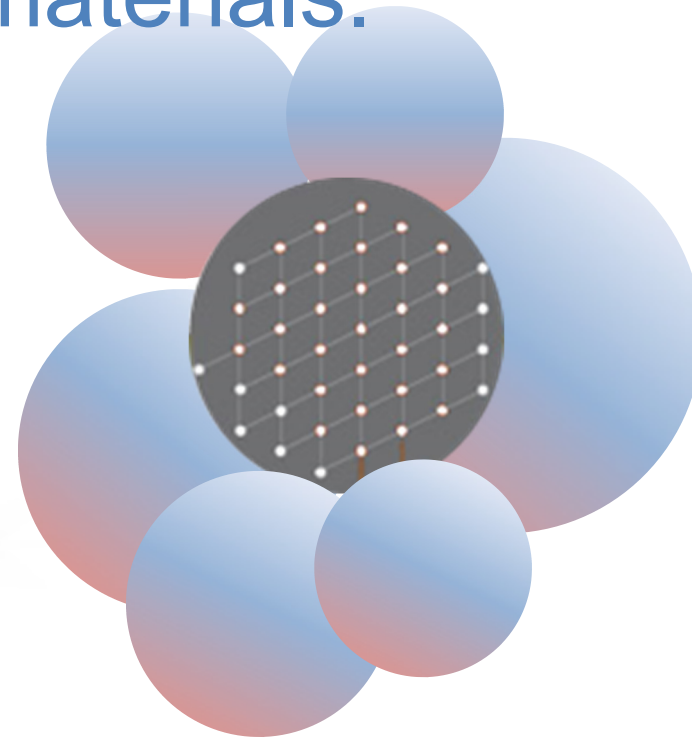
Mechatronic-oriented team dedicated to nano-positioning systems at SOLEIL.



Introduction – Context & overview

SWING Beamline, Synchrotron SOLEIL

A beamline that provides structural data at the nanometer-micrometer scale on soft condensed matter, macromolecules, and composite materials.



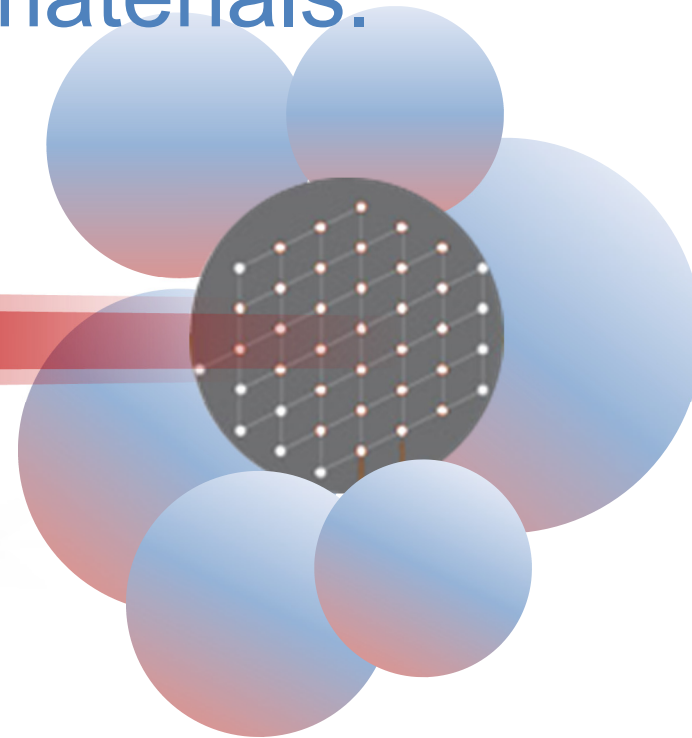


Introduction – Context & overview

SWING Beamline, Synchrotron SOLEIL

A beamline that provides structural data at the nanometer-micrometer scale on soft condensed matter, macromolecules, and composite materials.

Incident X-ray beam (5-16 keV)





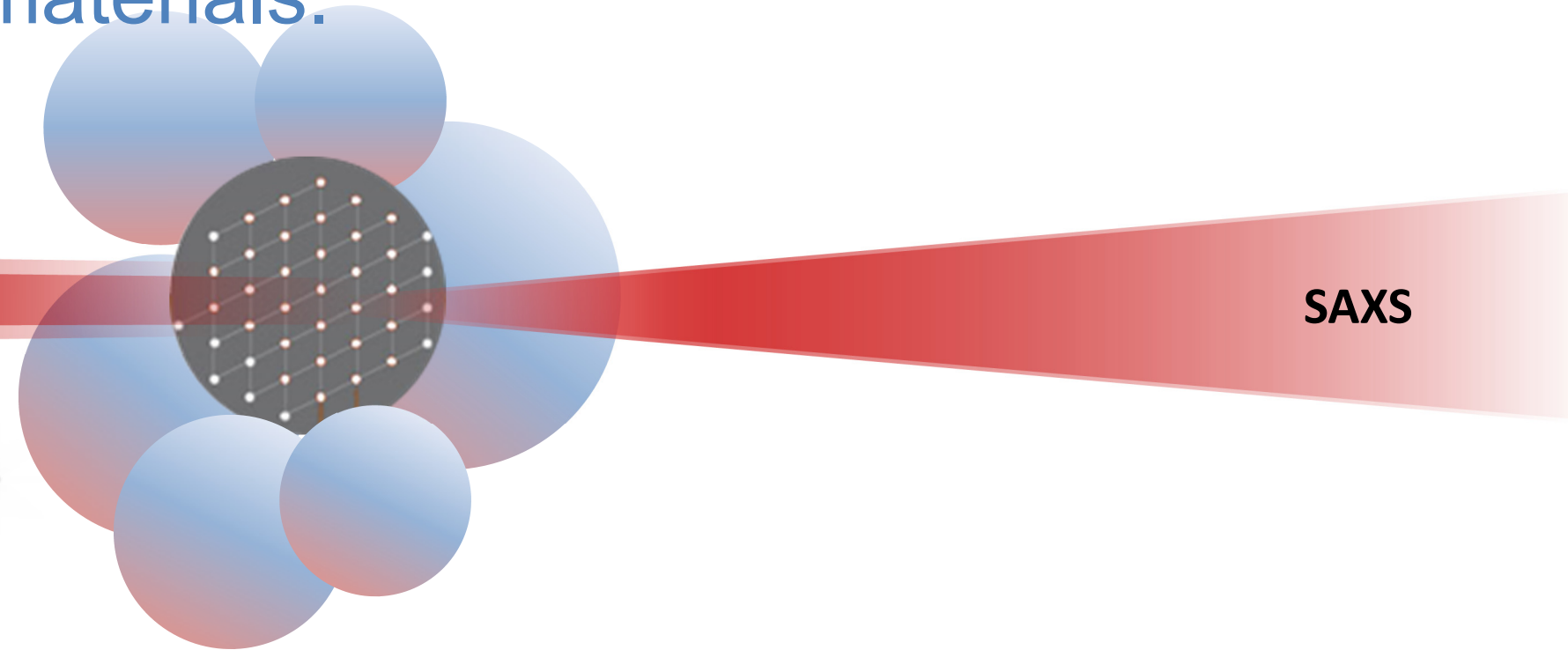
Introduction – Context & overview

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SAXS: Small-Angle X-ray Scattering





Introduction – Context & overview

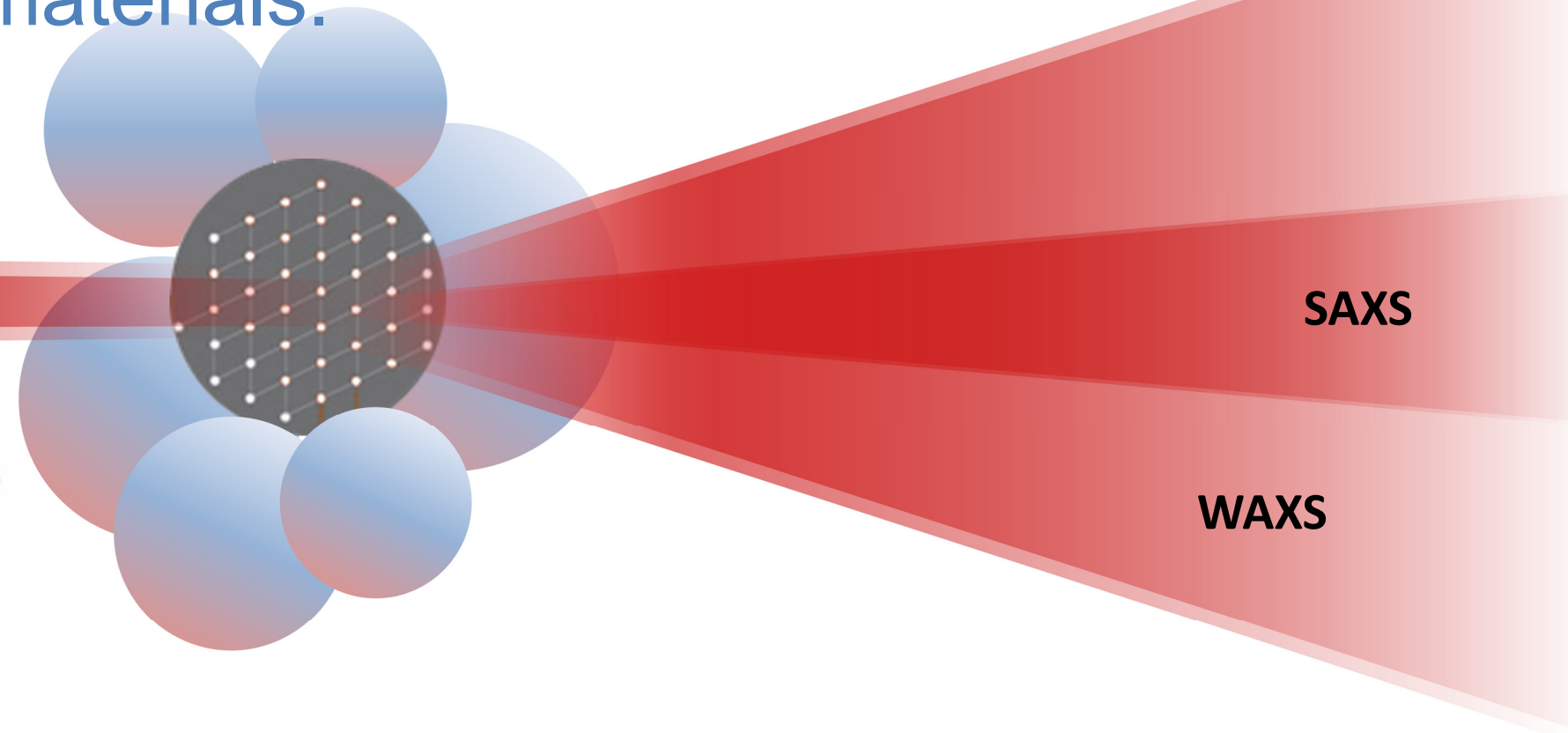
SWING Beamline, Synchrotron SOLEIL

A beamline that provides structural data at the nanometer-micrometer scale on soft condensed matter, macromolecules, and composite materials.

Incident X-ray beam (5-16 keV)

SAXS: **S**mall-**A**ngle **X**-ray **S**cattering

WAXS: **W**ide-**A**ngle **X**-ray **S**cattering





Introduction – Context & overview

SWING Beamline, Synchrotron SOLEIL

A beamline that provides structural data at the nanometer-micrometer scale on soft condensed matter, macromolecules, and composite materials.

GISAXS

SAXS

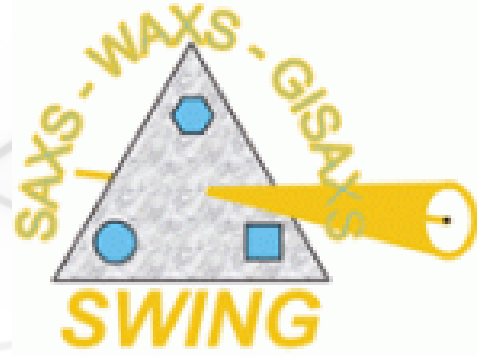
WAXS

Incident X-ray beam (5-16 keV)

SAXS: Small-Angle X-ray Scattering

WAXS: Wide-Angle X-ray Scattering

GISAXS: Grazing-Incidence X-ray Scattering



Introduction – Context & overview

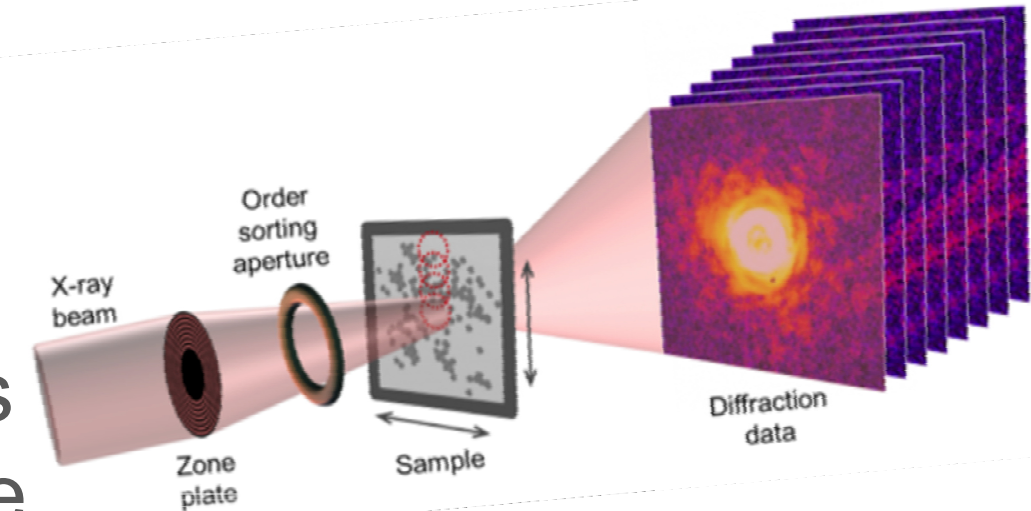
SWING Beamline, Synchrotron SOLEIL

2018 – Long-term objective

Implement *nano-tomo-ptychography* imaging on the beamline

(3D-Nano-Ptychography)

- Address a growing need amongst its users
- Prepare for upcoming synchrotron upgrade (higher coherence light source)



Nanoprobe SWING

Nanoprobe-SOLEIL

Nanopositioning working group

Nanoprobe Project
Prototype as outline

SWING Beamline

Introduce ptycho-imaging

Nanoprobe SWING

Objectives:

- Install a Nanoprobe system
- Qualify feasibility of 2D- ptychography on the SWING beamline with beam
- Qualify 2D scans using the Nanoprobe System

- Nanoprobe SWING Challenges
 - 2D-ptychography imaging resolutions of 20 nm
 - Sample sizes ranging from 10 μm up to a few 100 μm
 - Portable setup
- Approach
 - Support Structure & Environment: rigid & thermally stabilized
 - Stacked & modular designs
 - Interferometry
 - Tool to qualify and measure motion errors and be used for post-process image reconstructions
 - implemented in advanced modes of control

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 - Challenges & approach
- **Nanoprobe SWING Setup**
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S (Beam direction)

x

z

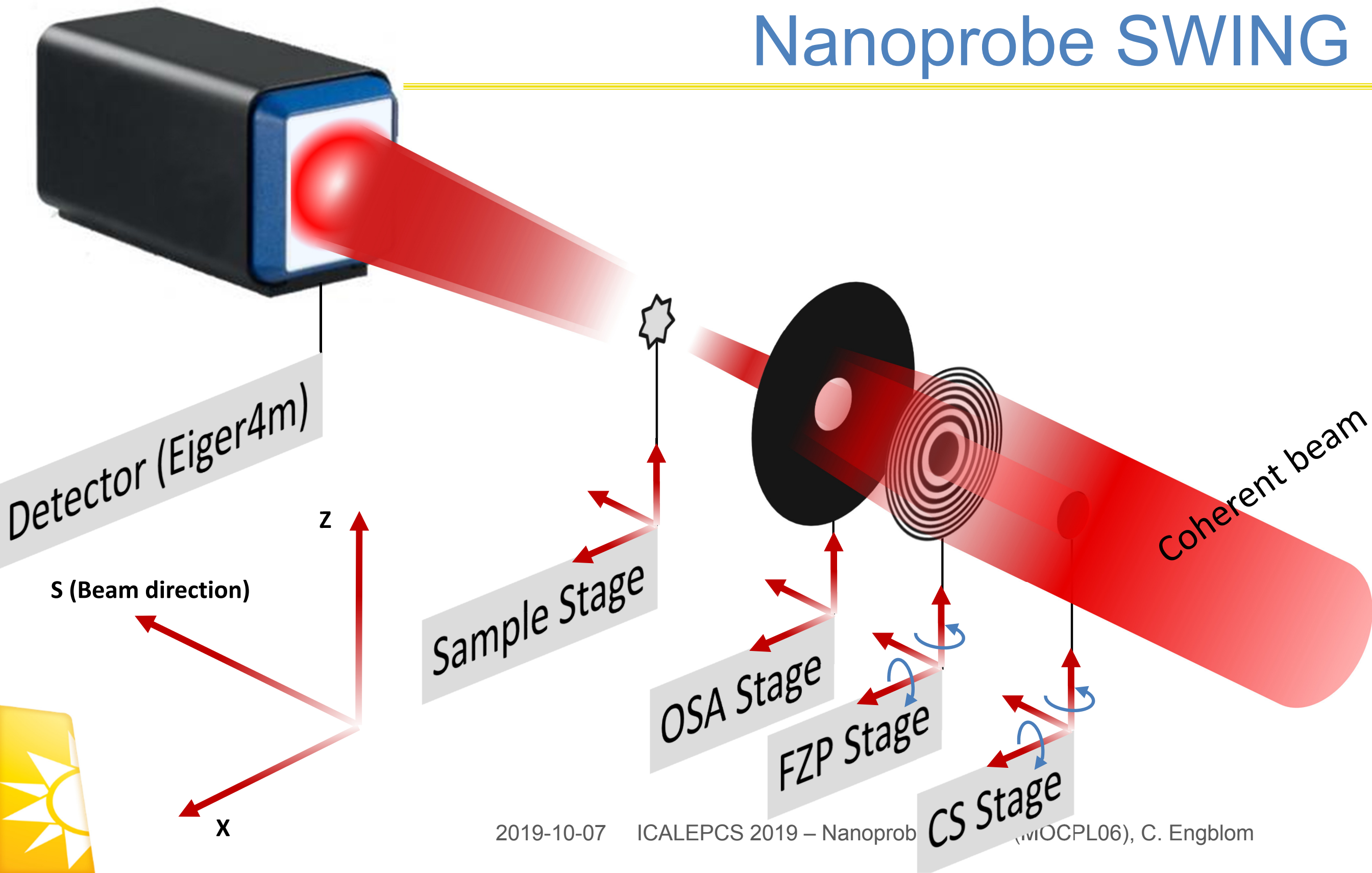
Experimental Hutch 1

Tunnel Detector (Eiger4M)

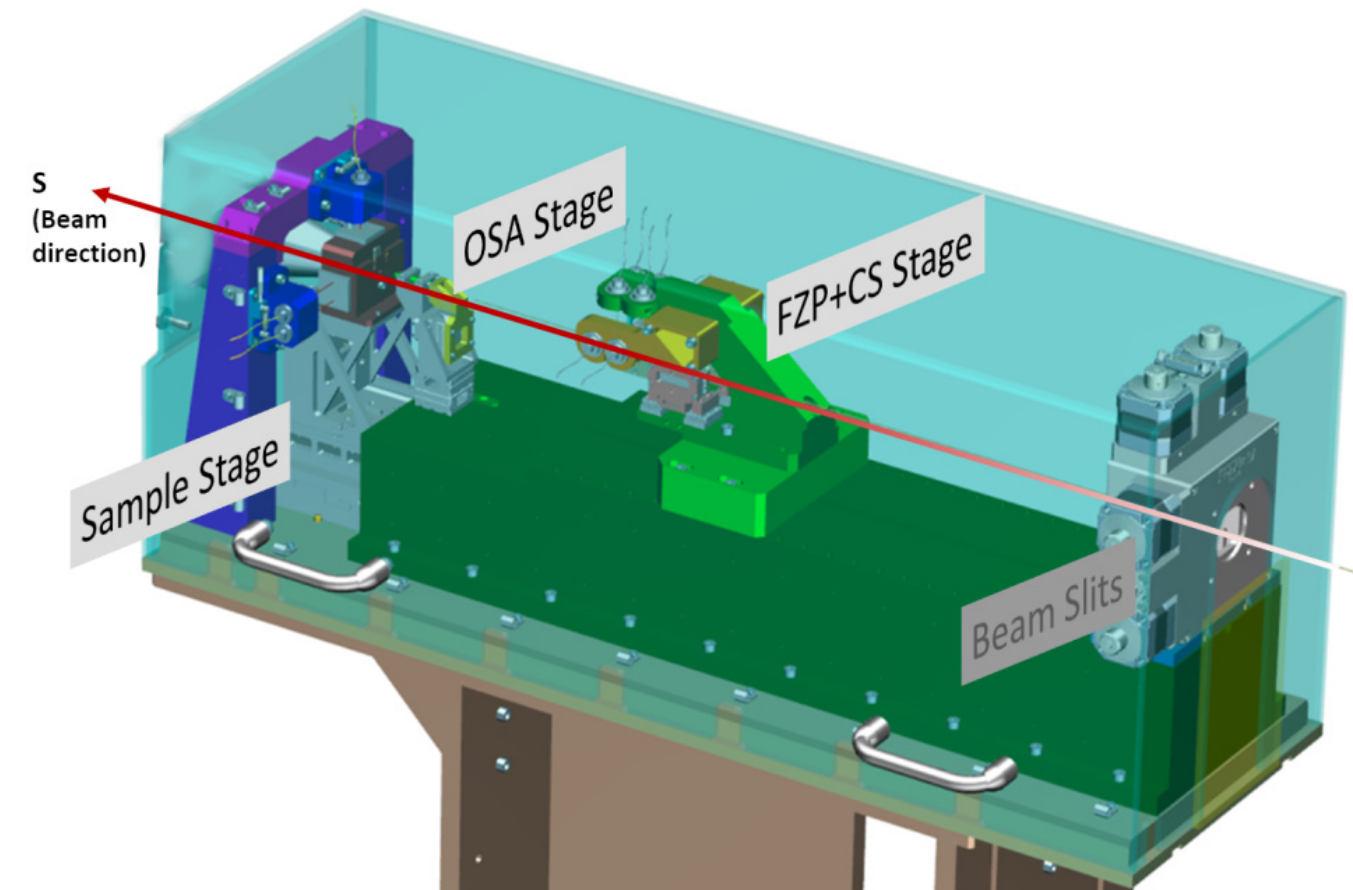
Nanoprobe System



Nanoprobe SWING Setup

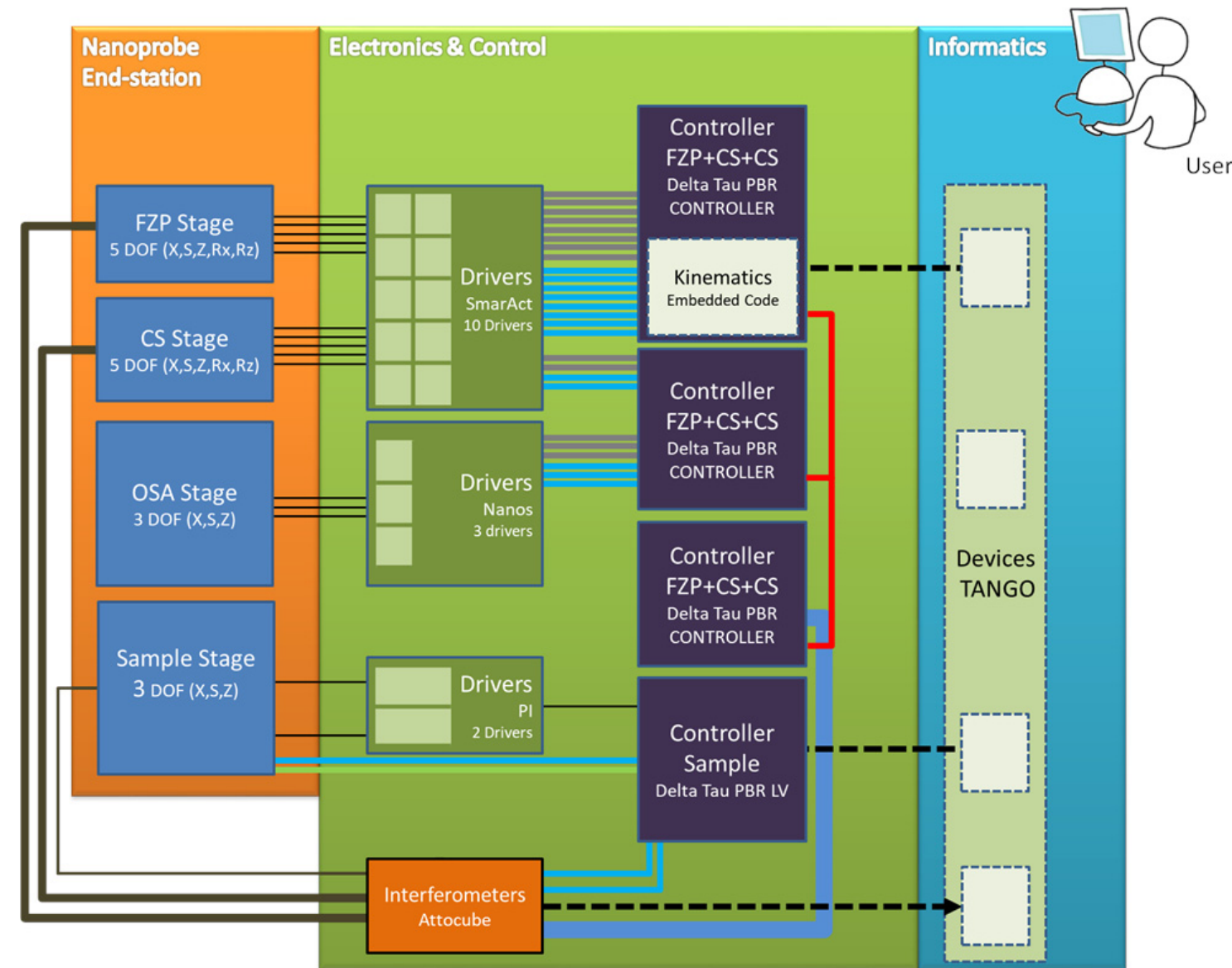


- Hutch environment stability ensured by performing vibrational analysis prior to installation
- Plexiglass enclosure added for:
 - Thermal stabilisation
 - Minimize air turbulence

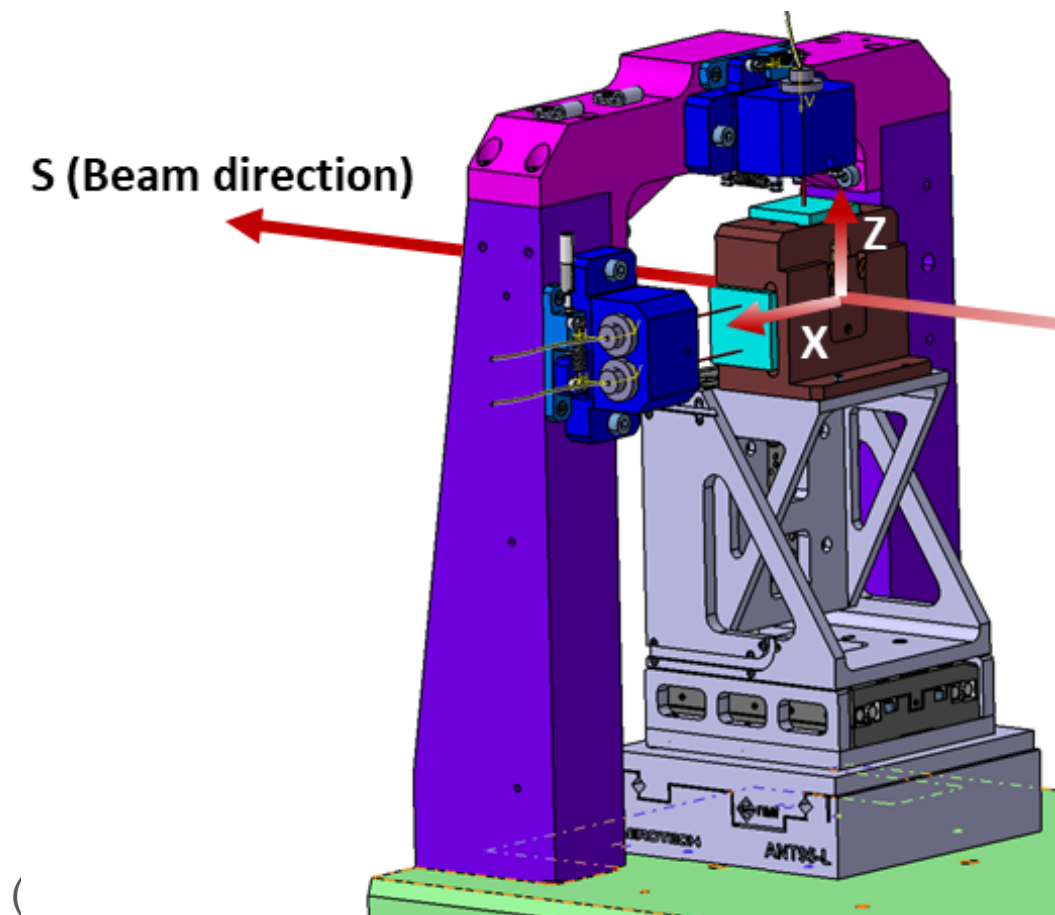


Control & Acquisition Architecture

- One-rack system
- Multiple Delta Tau Controllers (master-slave config)
 - Multi-axis Control (with kinematic models)
 - Interferometry used as feedback in control loops
- TANGO devices for high-level control



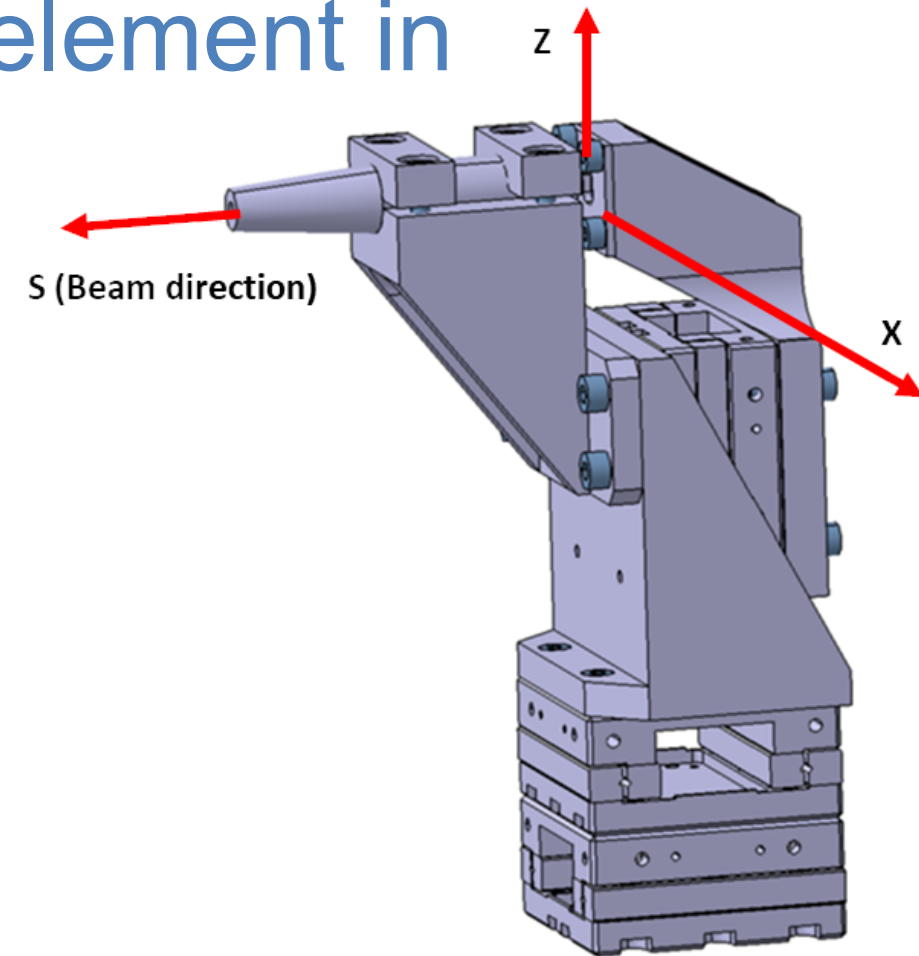
- Used for 2D sample scans in the XZ- plane
- Stacked design, actuating in 3 Degrees-Of-Freedom (DOF):
 - (X) → Linear Drive (Brushless),
 - (S,Z) → Linear Drives (Piezo multi-leg)
- Interferometer sensors: measuring motions errors in 3 DOF
 - Sample tracking for image reconstruction purposes

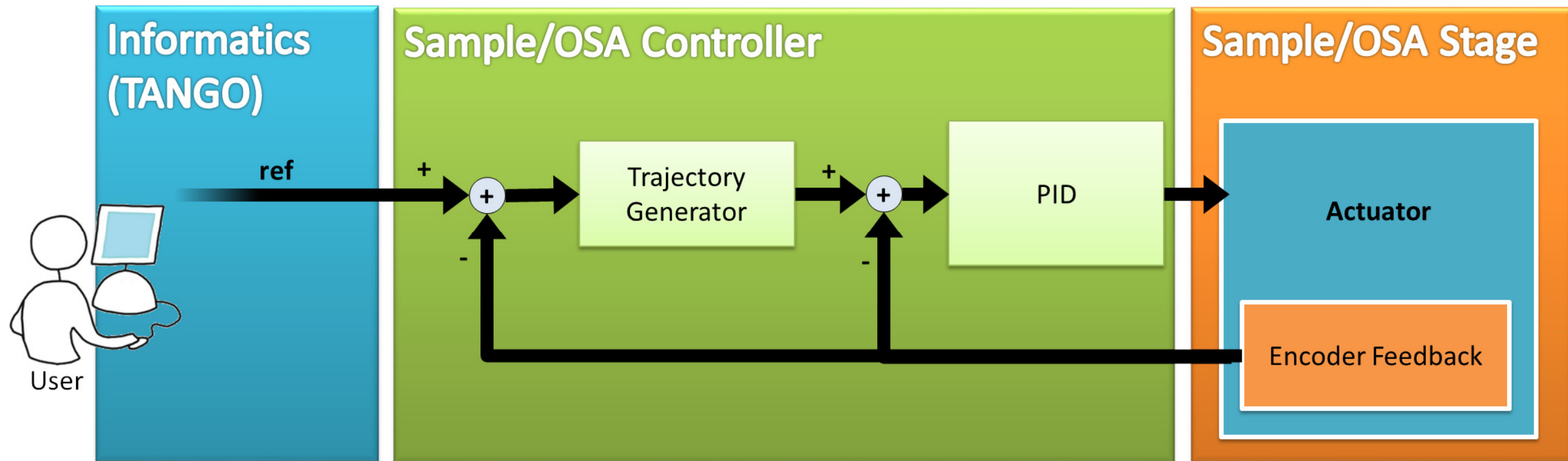


Nanoprobe SWING Setup

Order-Sorting-Aperture (OSA) Stage

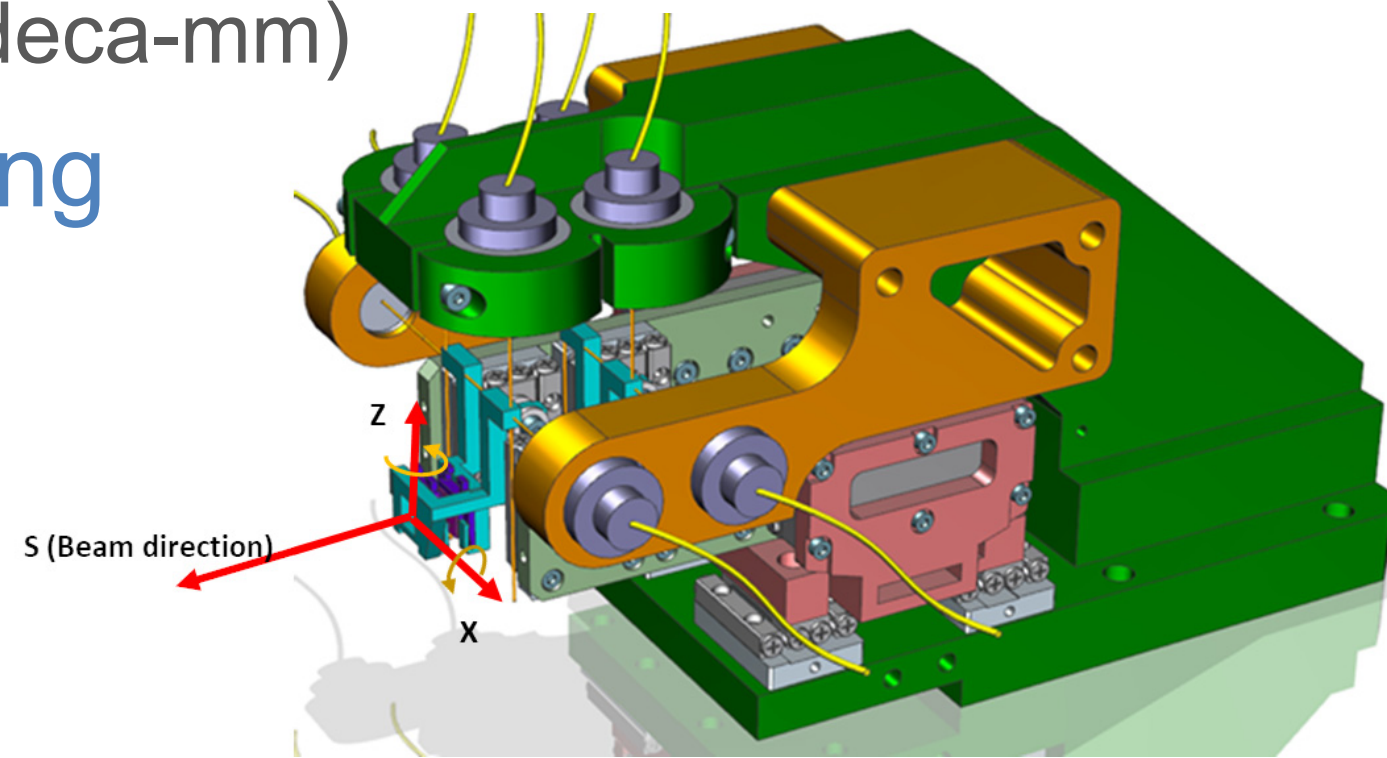
- Used for positioning and holding optical element
- Stacked design actuating the optical element in 3 DOF (X, S, Z)





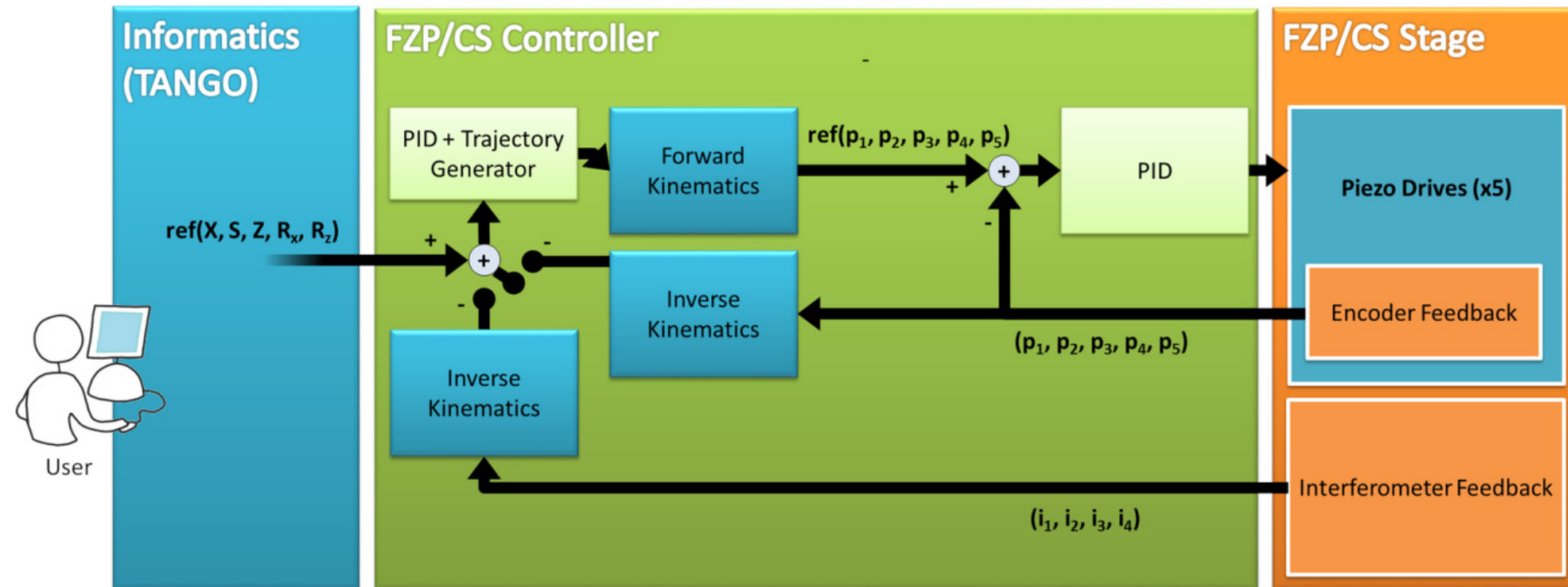
Fresnel Zone Plate (FZP)- & Central Stop (CS) Stages

- Two identical mirror-image modules for positioning and holding optical elements
- 5 x Linear Piezo-stick-slip drives
 - High-resolution (1nm), long-range (deca-mm)
- Stacked & parallel design actuating each optical element in 5 DOF (X, S, Z, Rx, Rz)



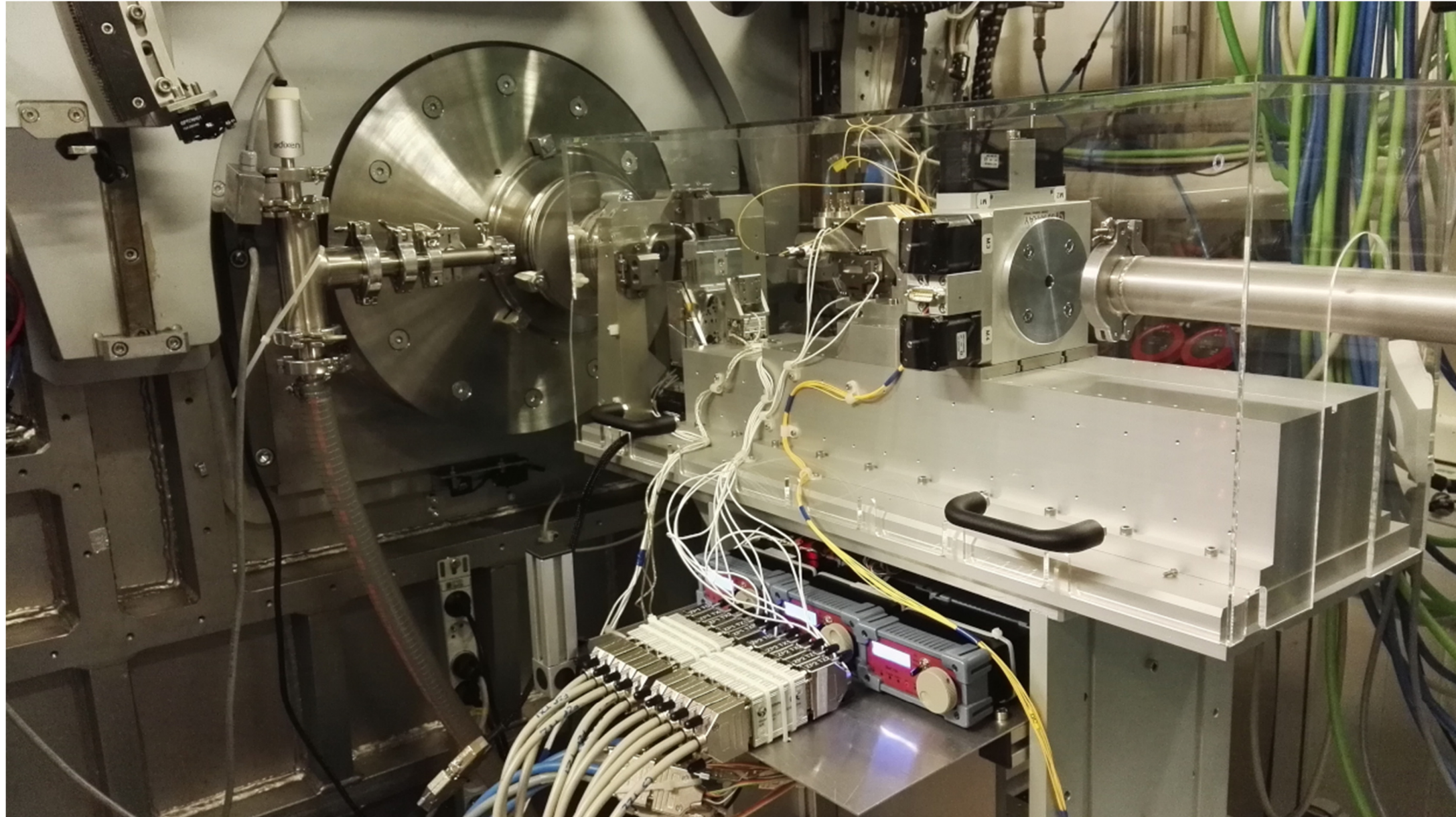
- Multi-axial cascade-loops

- Innermost loop: standard PID regulation with encoder feedback
- Outer loops: Kinematic conversions with encoder/interferometer feedback switching



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Experimental Hutch



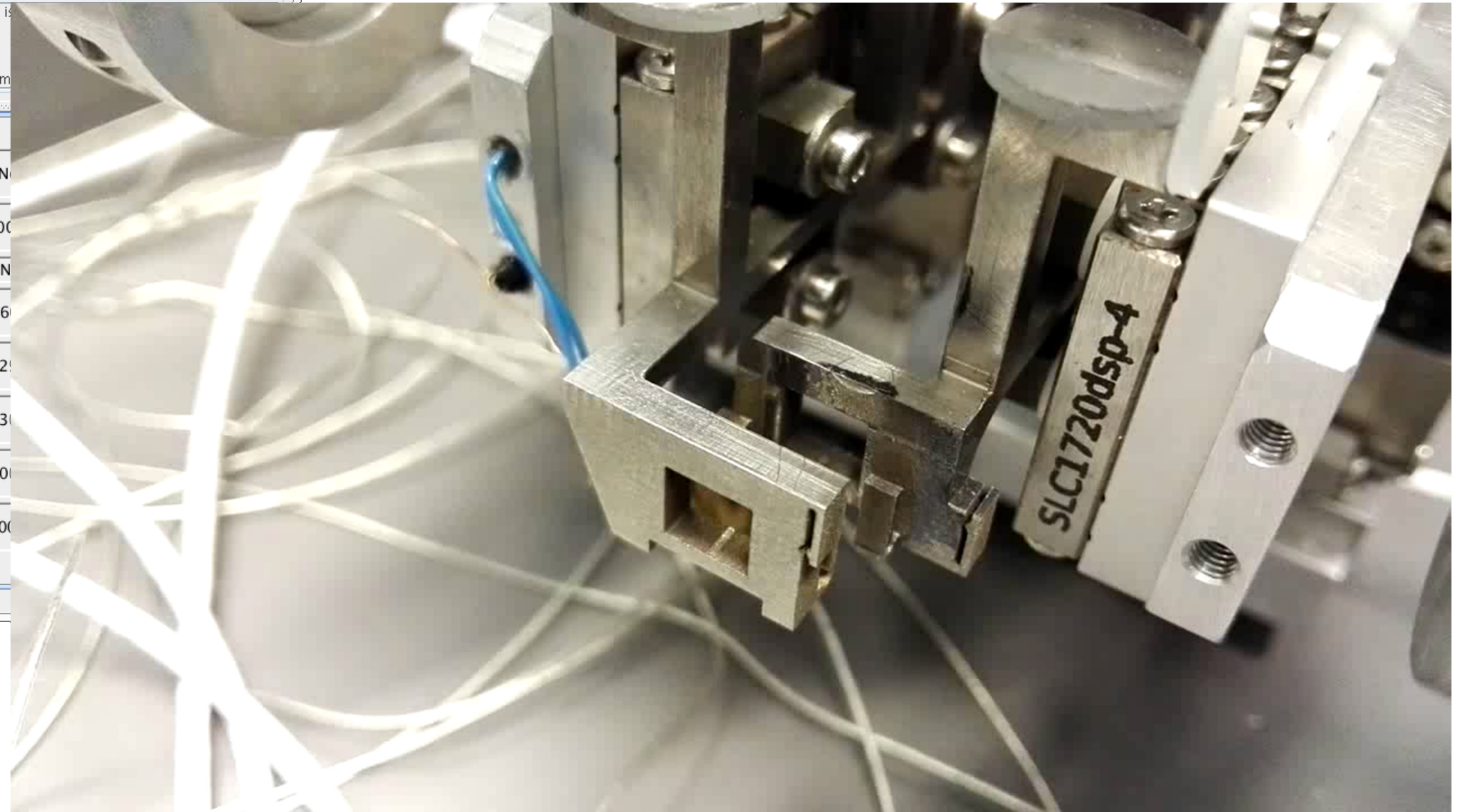
Experimental Hutch & Portability



Here with:
Filipe Alves – Mechanical Engineer
Javier Perez – Head of SWING beamline

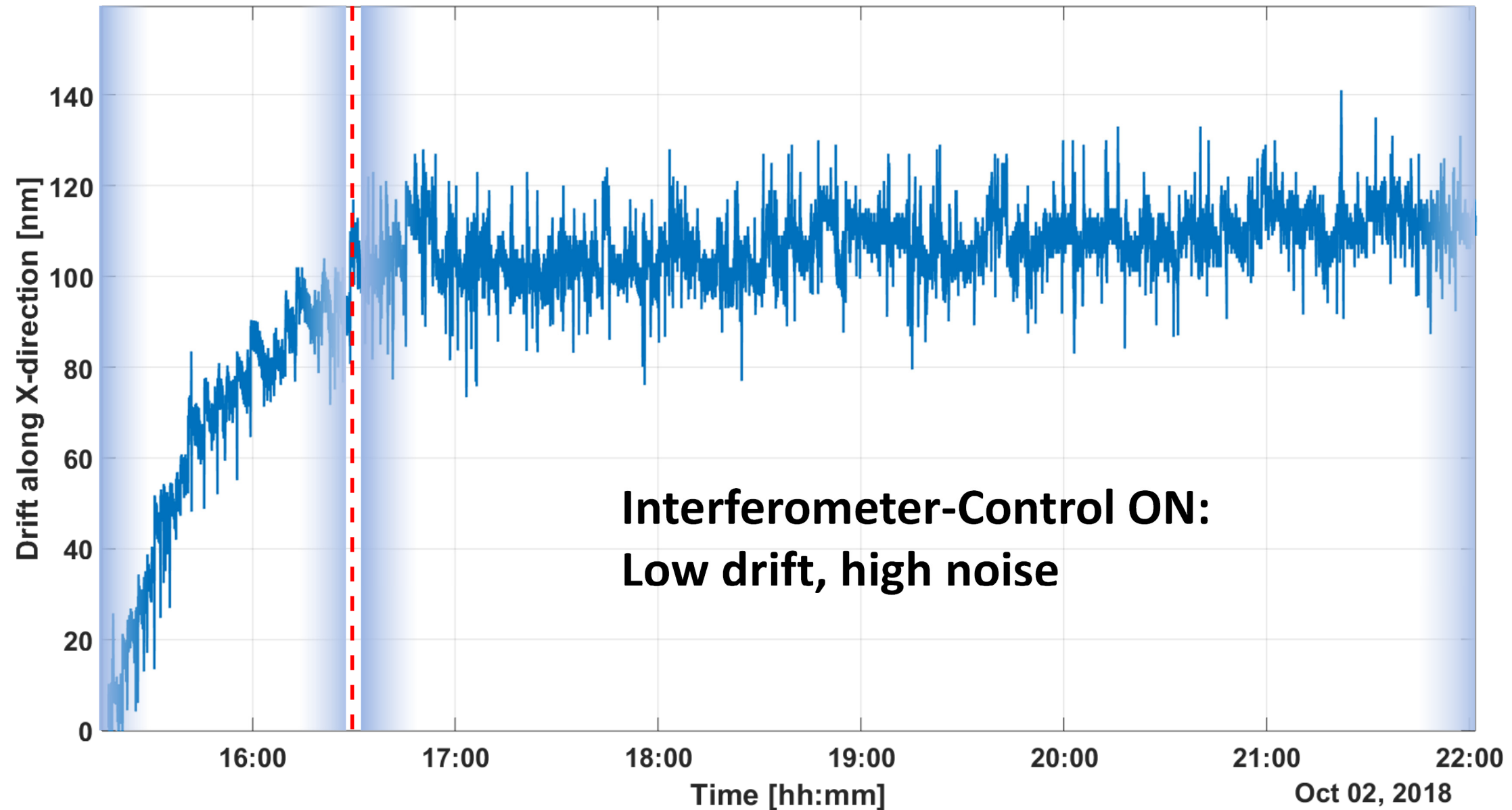
FZP/CS Control

The image shows two side-by-side screenshots of the AtkPanel 5.4 software interface. Both windows display the same control parameters for a device named 'PBR.TEST/CA/AXE-VIRTUAL' (left) and 'PBR.TEST/CA/AXE2-VIRTUAL' (right). The status is 'Stop' and 'Connection is open, Device is ready'. The 'Last started motion program' is '-- none --'. The 'movingMode' is set to '1 No unit' and 'movingTime' is '100.0 No unit'. The 'MP state' is 'NULL'. The 'FZP' (Focusing Zone Plate) parameters are: Rx = 2.60003°, Rz = 1.29997°, Ts = 0.52202 mm, Tx = 0.12005 mm, and Tz = 0.00005 mm. The 'CS' (Cathode System) parameters are: Rx = -2.6, Rz = 1.2, Ts = -1.23, Tx = -0.00, and Tz = 0.10.

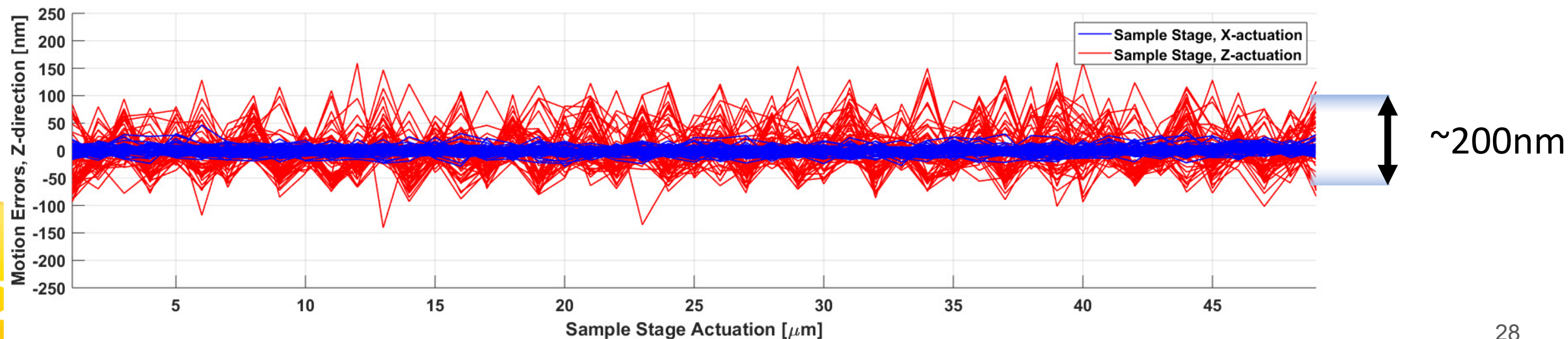
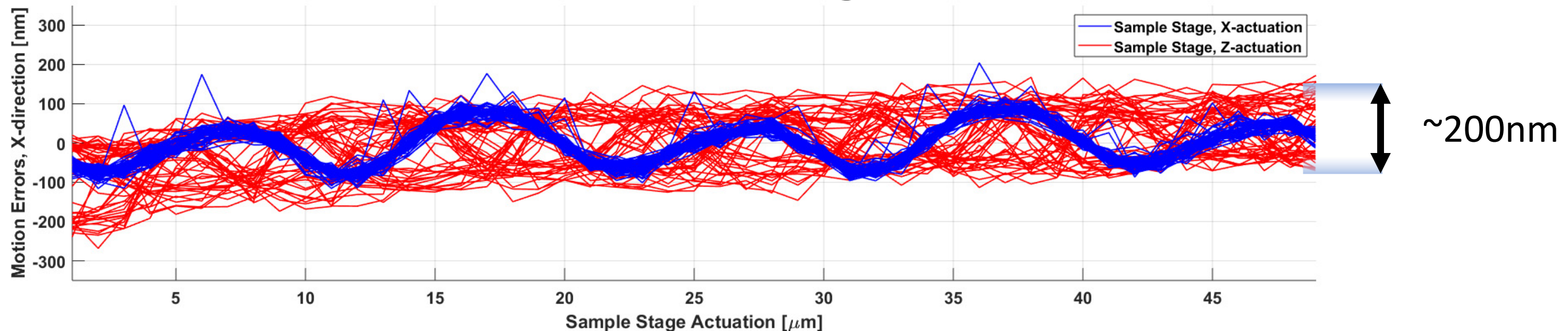


**Interferometer-Control OFF:
High drift, low noise**

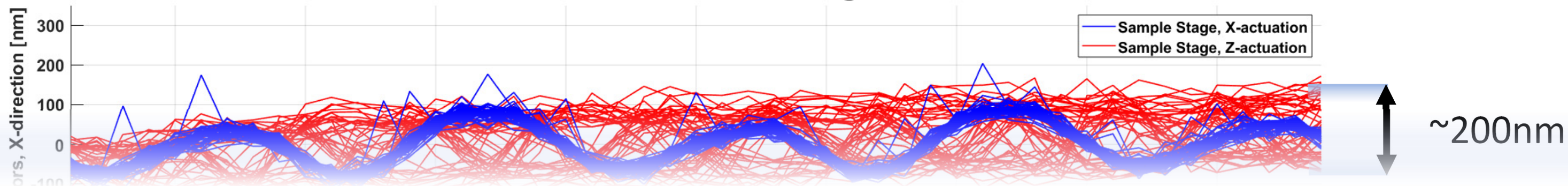
FZP/CS Control



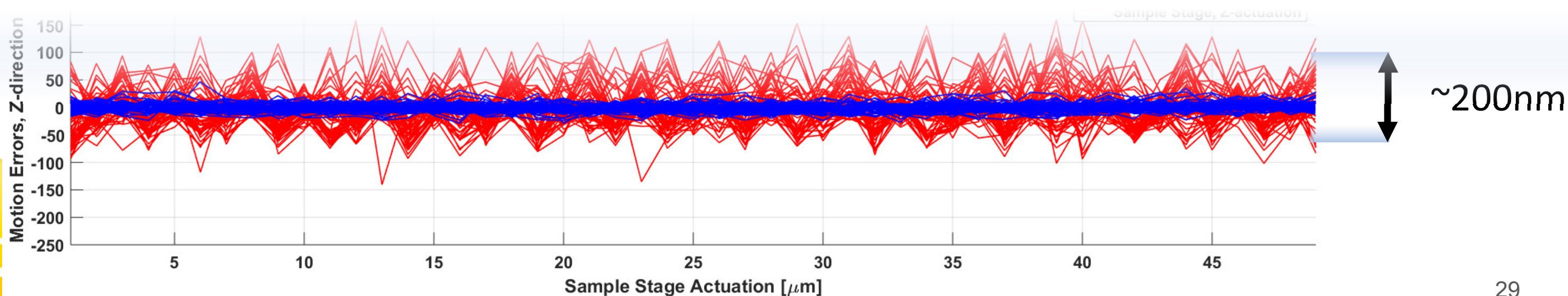
Sample Stage, Motion Errors



Sample Stage, Motion Errors



Interferometry is crucial to resolve the nanometer

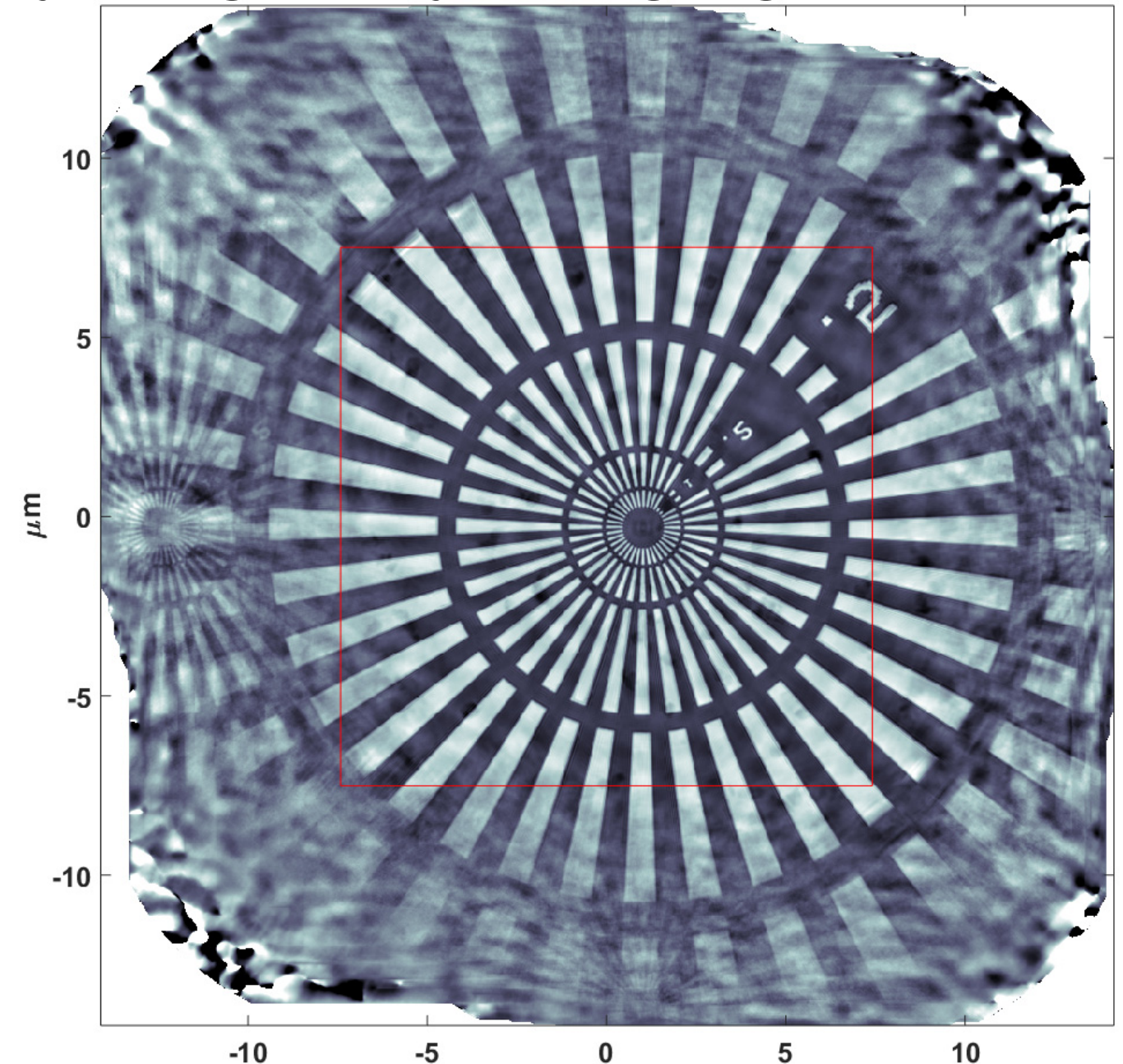


2D-Nano-Ptychography Imaging Results

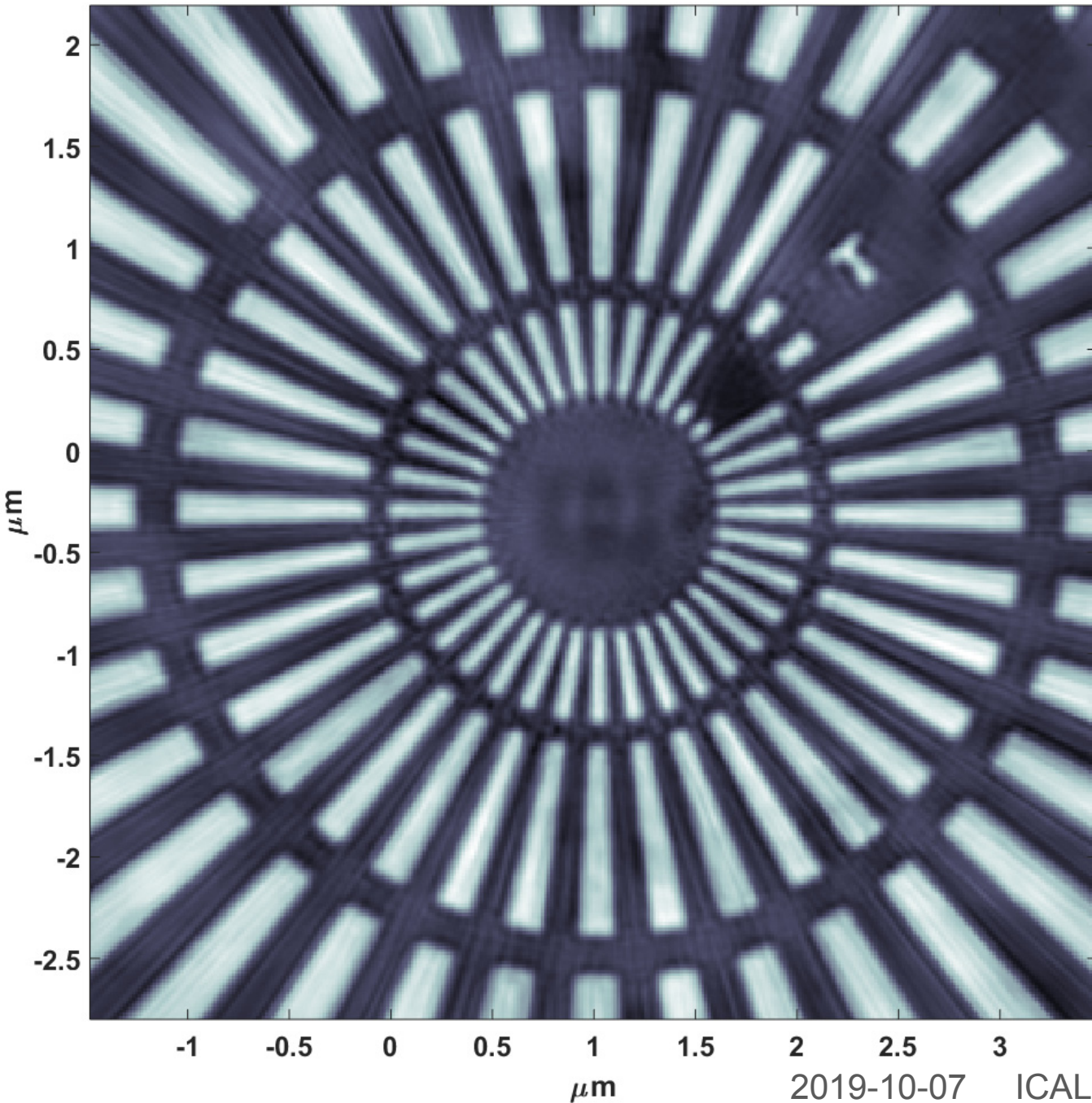
- Sample: Siemens Star (50nm inner-most spokes)
- 2D-imaging (with beam)
 - 15x15 μm scan
 - 500 nm steps
 - **Interferometer Sample tracking**
 - **Image reconstructions**

2D-Nano-Ptychography Imaging Results

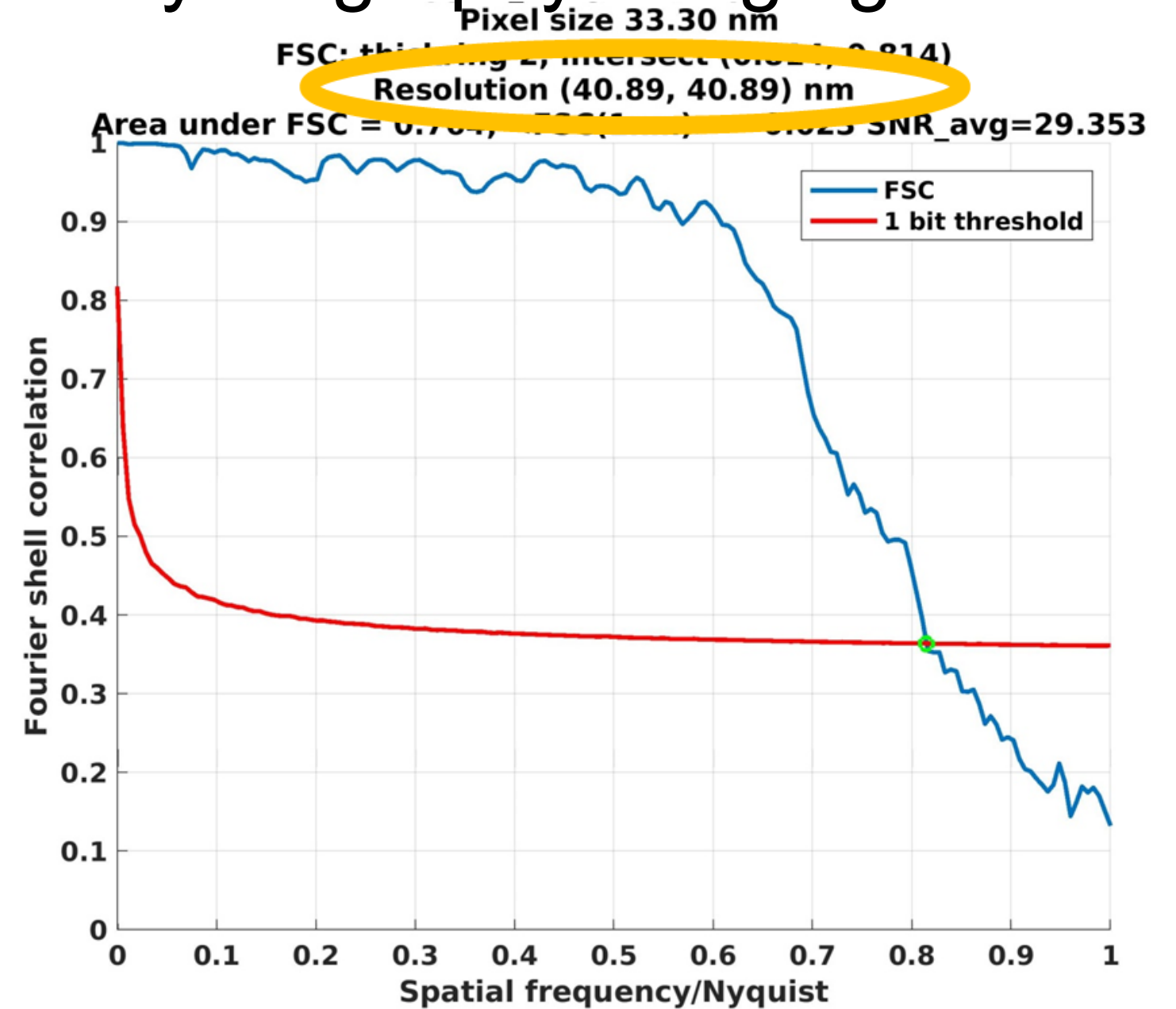
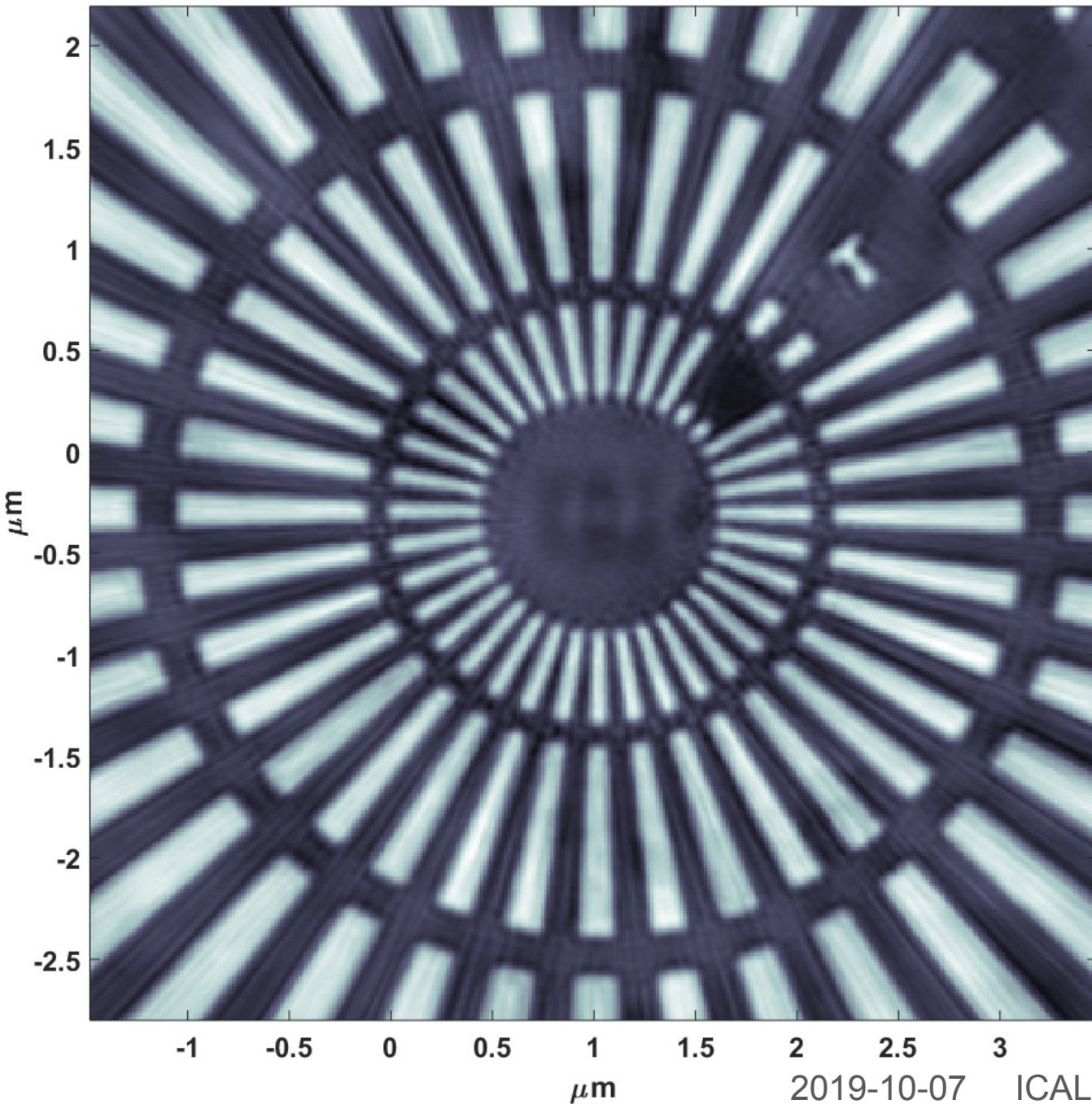
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2D-Nano-Ptychography Imaging Results



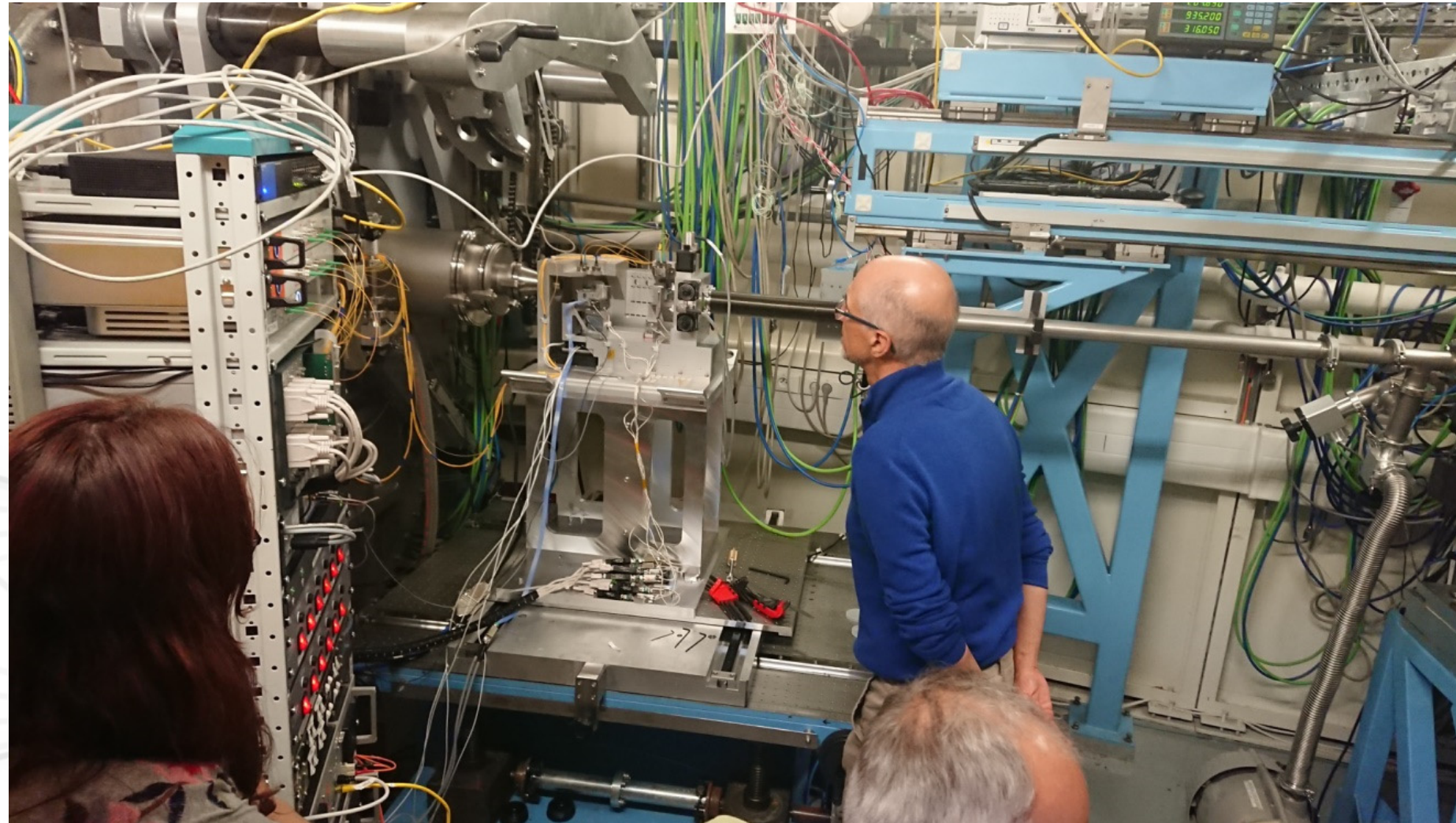
2D-Nano-Ptychography Imaging Results



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- **System portability**
 - Objective achieved, system could be installed/uninstalled within hours
- **2D-nano-ptychography imaging capabilities**
 - Resolution (image repeatability) = ~ 40 nm
 - **Not yet there, but a on good start!**

- Where do we go from here?
 - Better 2D-resolution
 - To 3D from 2D



3D-Nano-ptychography implementations ongoing...

2D-Nano-Ptychography Imaging Results on the SWING Beamline at Synchrotron SOLEIL (MOCPL06)

Nanoprobe Results: Metrology & Control in stacked closed-loop systems (WEAPL04)

<http://accelconf.web.cern.ch/AccelConf/icalepcs2017/papers/weapl04.pdf>

Nanoprobe Project – Sample Stage Control (MOCRAF 2015)

<https://www.synchrotron-soleil.fr/fr/file/8047/download?token=luXoXhmR>